

# Resource Summary Report

Generated by SPARC SAWG on Aug 5, 2026

## FEI: Helios G4 UX

RRID:SCR\_021773

Type: Tool

### Proper Citation

FEI: Helios G4 UX (RRID:SCR\_021773)

### Resource Information

**URL:** <http://www.mcpf.hkust.edu.hk/service.php?id=PE022>

**Proper Citation:** FEI: Helios G4 UX (RRID:SCR\_021773)

**Description:** Dual beam FIB/FESEM system, containing both focused Ga plus ion beam and ultra high resolution field emission scanning electron column and their combined use. Dual beam focused ion beam scanning electron microscope for nanofabrication.

**Synonyms:** Helios G4 UX

**Resource Type:** instrument resource

**Keywords:** FIB, SEM, nanofabrication, dual beam, focused ion beam, scanning electron microscope, USEDit

**Availability:** Commercially available

**Resource Name:** FEI: Helios G4 UX

**Resource ID:** SCR\_021773

**Alternate IDs:** Model\_Number\_FEI Helios G4 UX

**Record Creation Time:** 20220129T080357+0000

**Record Last Update:** 20260801T190717+0000

### Ratings and Alerts

No rating or validation information has been found for FEI: Helios G4 UX.

No alerts have been found for FEI: Helios G4 UX.

### Data and Source Information

**Source:** [SciCrunch Registry](#)

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## Usage and Citation Metrics

We found 1 mentions in open access literature.

**Listed below are recent publications.** The full list is available at [SPARC SAWG](#) .

Ichikawa T, et al. (2023) Protocol for live imaging of intracellular nanoscale structures using atomic force microscopy with nanoneedle probes. STAR protocols, 4(3), 102468.